

PATENT APPLICATION *1R*

IN THE U.S. PATENT AND TRADEMARK OFFICE

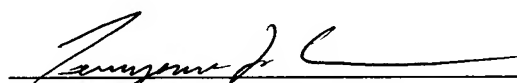
Applicant: Satoshi FURUTA
Title: METHOD FOR MANUFACTURE OF ESTERS BY
TRANSESTERIFICATION
Serial No.: 10/558 935 Group: 1621
Confirmation No.: 6397
Filed: December 1, 2005 Examiner: Katakam
International Application No.: PCT/JP2004/009250
International Filing Date: June 23, 2004
Atty. Docket No.: 4700.P0320US

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

FIRST CLASS MAILING CERTIFICATE

Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service under 37 CFR 1.8 as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on January 11, 2007.


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	Donald J. Wallace	Reg. No. 43 977
	Sidney B. Williams, Jr.	Reg. No. 24 949

Correspondence: Information Disclosure Statement
dated January 11, 2007
including enclosures listed thereon

190.05/05



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INFORMATION DISCLOSURE STATEMENT

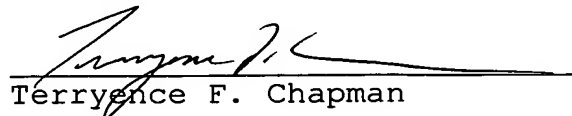
Sir:

In compliance with the provisions of Rules 1.97(e)(1) and 1.98, enclosed herewith is a copy of the European Patent Office Search Report, Form PTO-1449 and the references cited thereon. The relevance of these references is explained on the enclosed search report. Accordingly, further comment at this point in time should not be necessary.

I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Further consideration is respectfully solicited.

Respectfully submitted,


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Encl: Copy of European Patent Office Search Report
dated October 19, 2006 (3 pages)
Form PTO-1449 and references cited thereon
Postal Card

INFORMATION DISCLOSURE CITATION
 Applicant: Satoshi FURUTA
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U.S. PATENT DOCUMENTS

Examiner Initials*	No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA	6 090 959	07-18-2000	HIRANO et al
	AB			
	AC			
	AD			
	AE			
	AF			
	AG			
	AH			
	AI			
	AJ			
	AK			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AL	EP 1 505 048 A1	02-09-2005	LACOME et al	
	AM				
	AN				
	AO				
	AP				

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AQ	
	AR	
EXAMINER SIGNATURE		DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.